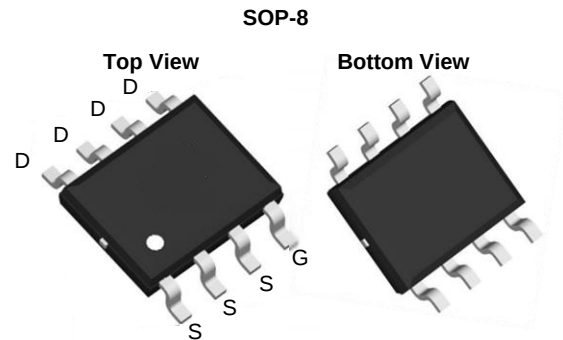
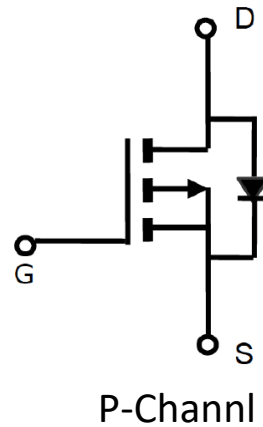


- -30V/-15A
- $R_{DS(ON)}=5.5m\Omega$ (typ) @VGS=10V
 $R_{DS(ON)}=9m\Omega$ (typ) @VGS=4.5V
- 100% UIS & RG Tested
- Reliable and Rugged
- Lead Free and Green Devices Available (RoHS Compliant)



Applic

- Power Management for Industrial DC/DC Converters



Absolute Maximum Ratings (T_A= 25°C unless otherwise noted)

Symbol	Parameter	Maximum	Units
V _{DS}	Drain-Source Voltage	-30	V
V _{GS}	Gate-Source Voltage	±25	V
I _D	Continuous Drain Current	-16	A
	T _A =25°C	-12.5	
I _{DM}	Pulsed Drain Current ^C	-64	A
I _{AS}	Avalanche Current ^C	39	A
E _{AS}	Avalanche energy ^C L=0.1mH	76	mJ
P _D	Power Dissipation ^B	3.1	W
	T _A =25°C	2.0	
T _J , T _{STG}	Junction and Storage Temperature Range	-55 to 150	°C

Thermal Characteristics

Symbol	Parameter	Typ	Max	Units
R _{θJA}	Maximum Junction-to-Ambient ^A	31	40	°C/W
	Maximum Junction-to-Ambient ^{A D}	59	75	°C/W
R _{θJL}	Maximum Junction-to-Lead	16	24	°C/W

Electrical Characteristics ($T_J=25^{\circ}\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}$, $V_{GS}=0\text{V}$	-30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-24\text{V}$, $V_{GS}=0\text{V}$ $T_J=55^{\circ}\text{C}$			-1 -5	μA
advanced	Gate-Body leakage current	$V_{DS}=0\text{V}$, $V_{GS}=\pm 25\text{V}$			± 100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D=-250\mu\text{A}$	-1	-1.8	-2.7	V
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}$, $I_D=-15\text{A}$ $T_J=125^{\circ}\text{C}$		5.5 7.6	7.2 10.5	m Ω
		$V_{GS}=-4.5\text{V}$, $I_D=-10\text{A}$		9	12	m Ω
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}$, $I_D=-16\text{A}$		50		S
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}$, $V_{GS}=0\text{V}$		-0.7	-1	V
I_S	Maximum Body-Diode Continuous Current				-4	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}$, $V_{DS}=-15\text{V}$, $f=1\text{MHz}$		3560		pF
C_{oss}	Output Capacitance			635		pF
C_{rss}	Reverse Transfer Capacitance			645		pF
R_g	Gate resistance	$f=1\text{MHz}$		8		Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=-10\text{V}$, $V_{DS}=-15\text{V}$, $I_D=-16\text{A}$		50	70	nC
$Q_g(4.5\text{V})$	Total Gate Charge			25	35	nC
Q_{gs}	Gate Source Charge			9		nC
Q_{gd}	Gate Drain Charge			12		nC
$t_{D(on)}$	Turn-On DelayTime	$V_{GS}=-10\text{V}$, $V_{DS}=-15\text{V}$, $R_L=0.95\Omega$, $R_{GEN}=3\Omega$		12		ns
t_r	Turn-On Rise Time			12.5		ns
$t_{D(off)}$	Turn-Off DelayTime			135		ns
t_f	Turn-Off Fall Time			63		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-16\text{A}$, $di/dt=500\text{A}/\mu\text{s}$		32		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-16\text{A}$, $di/dt=500\text{A}/\mu\text{s}$		62		nC

A. The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^{\circ}\text{C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(MAX)}=150^{\circ}\text{C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)}=150^{\circ}\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^{\circ}\text{C}$.

D. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to lead $R_{\theta JL}$ and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(MAX)}=150^{\circ}\text{C}$. The SOA curve provides a single pulse rating.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

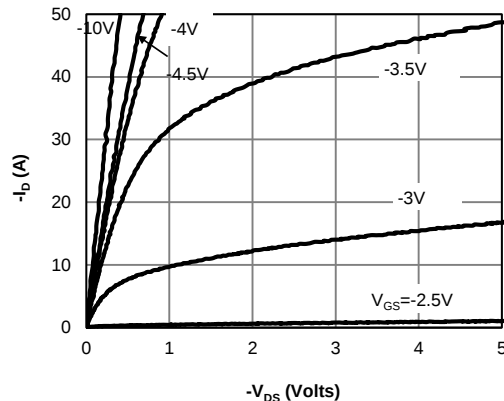


Figure 1: On-Region Characteristics (Note E)

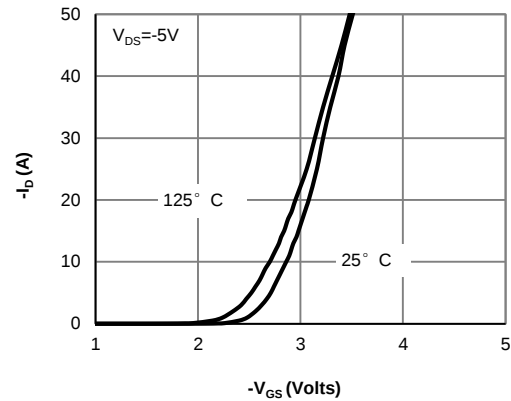


Figure 2: Transfer Characteristics (Note E)

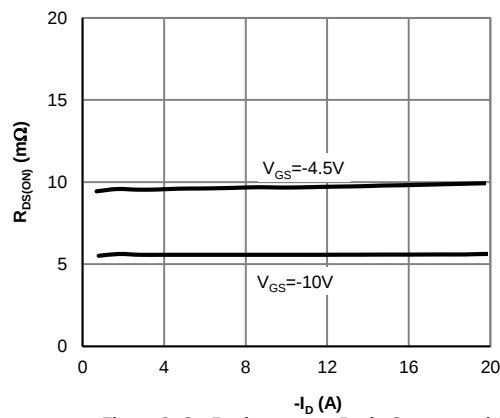


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

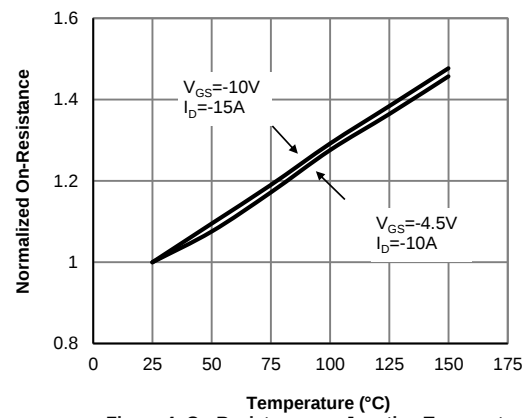


Figure 4: On-Resistance vs. Junction Temperature (Note E)

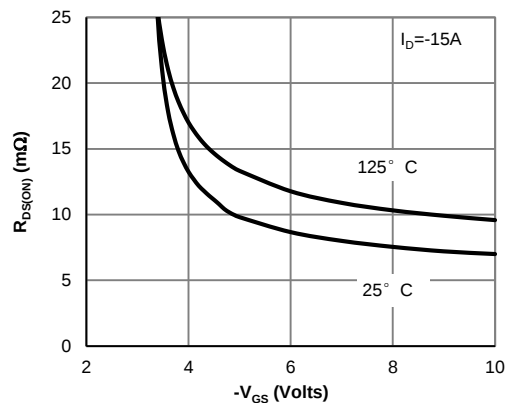


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

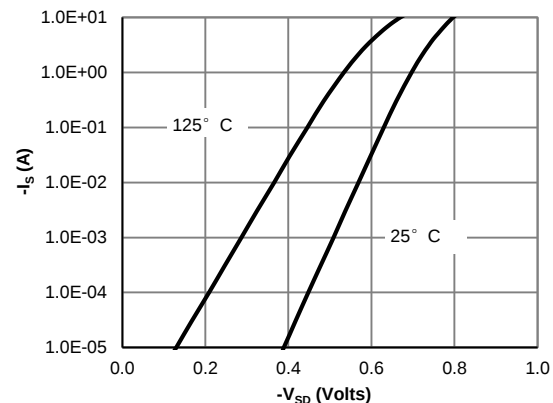


Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

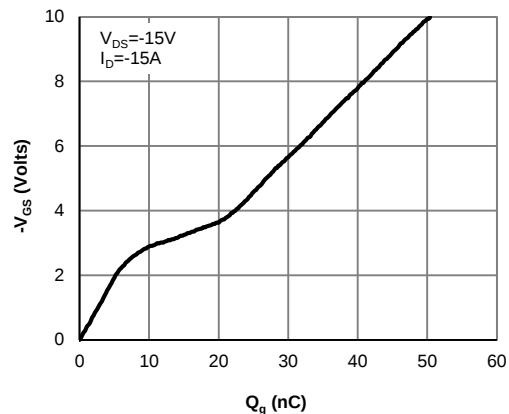


Figure 7: Gate-Charge Characteristics

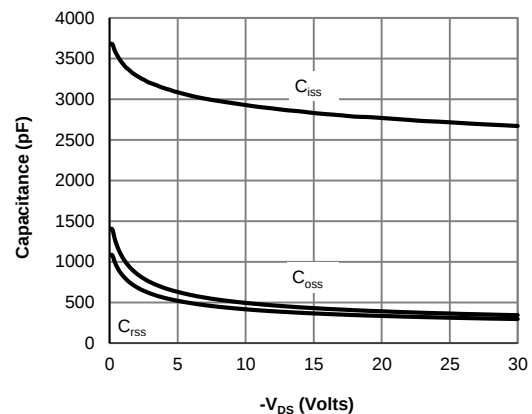


Figure 8: Capacitance Characteristics

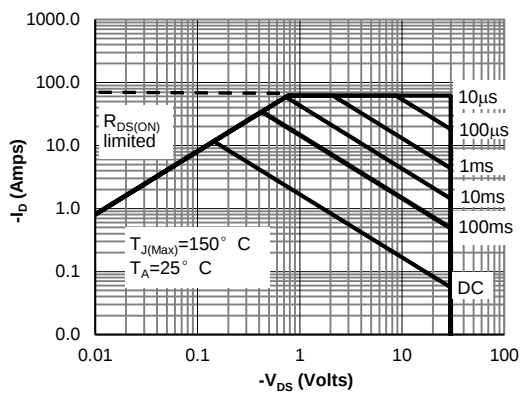


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

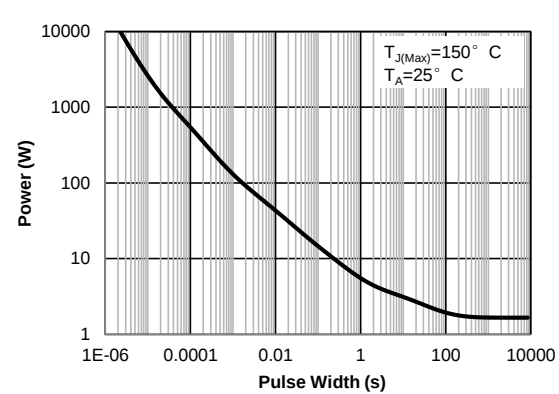


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

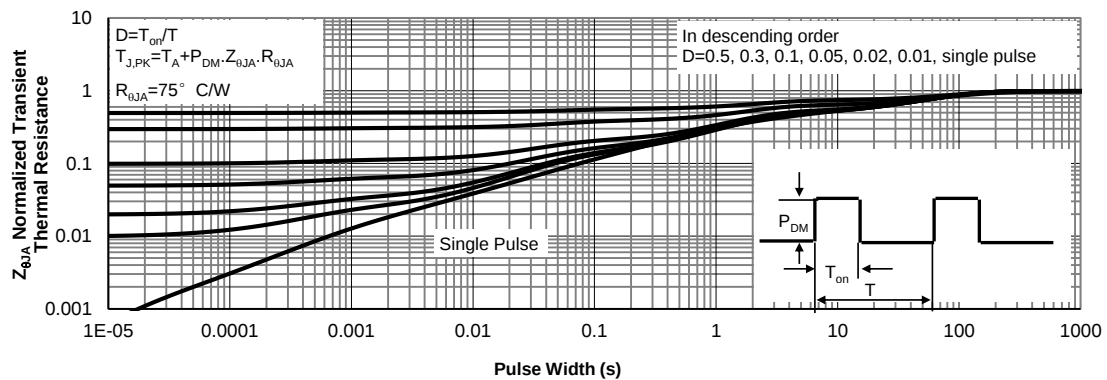
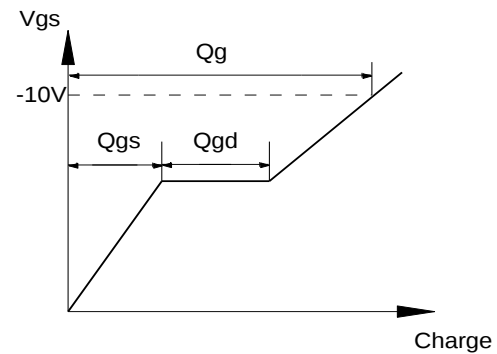
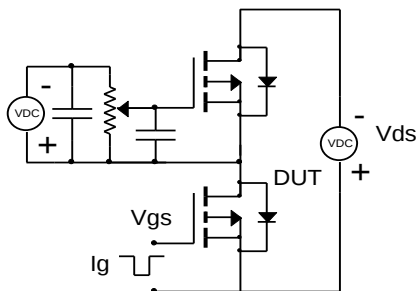
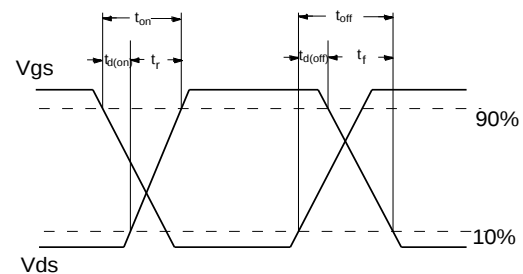
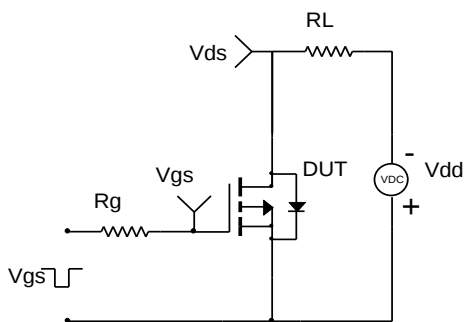


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

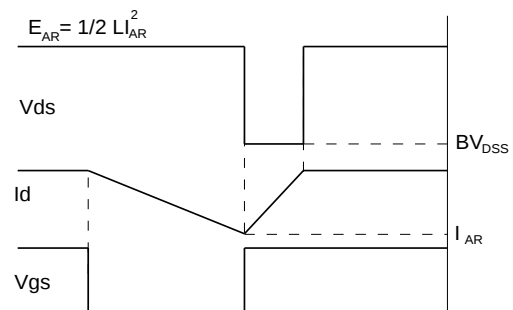
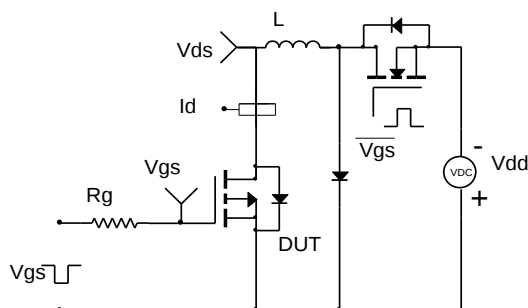
Gate Charge Test Circuit & Waveform



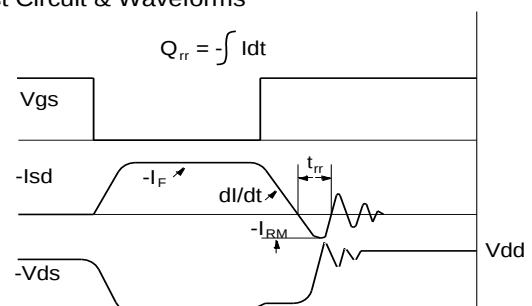
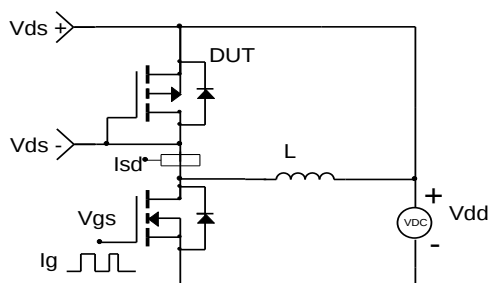
Resistive Switching Test Circuit & Waveforms



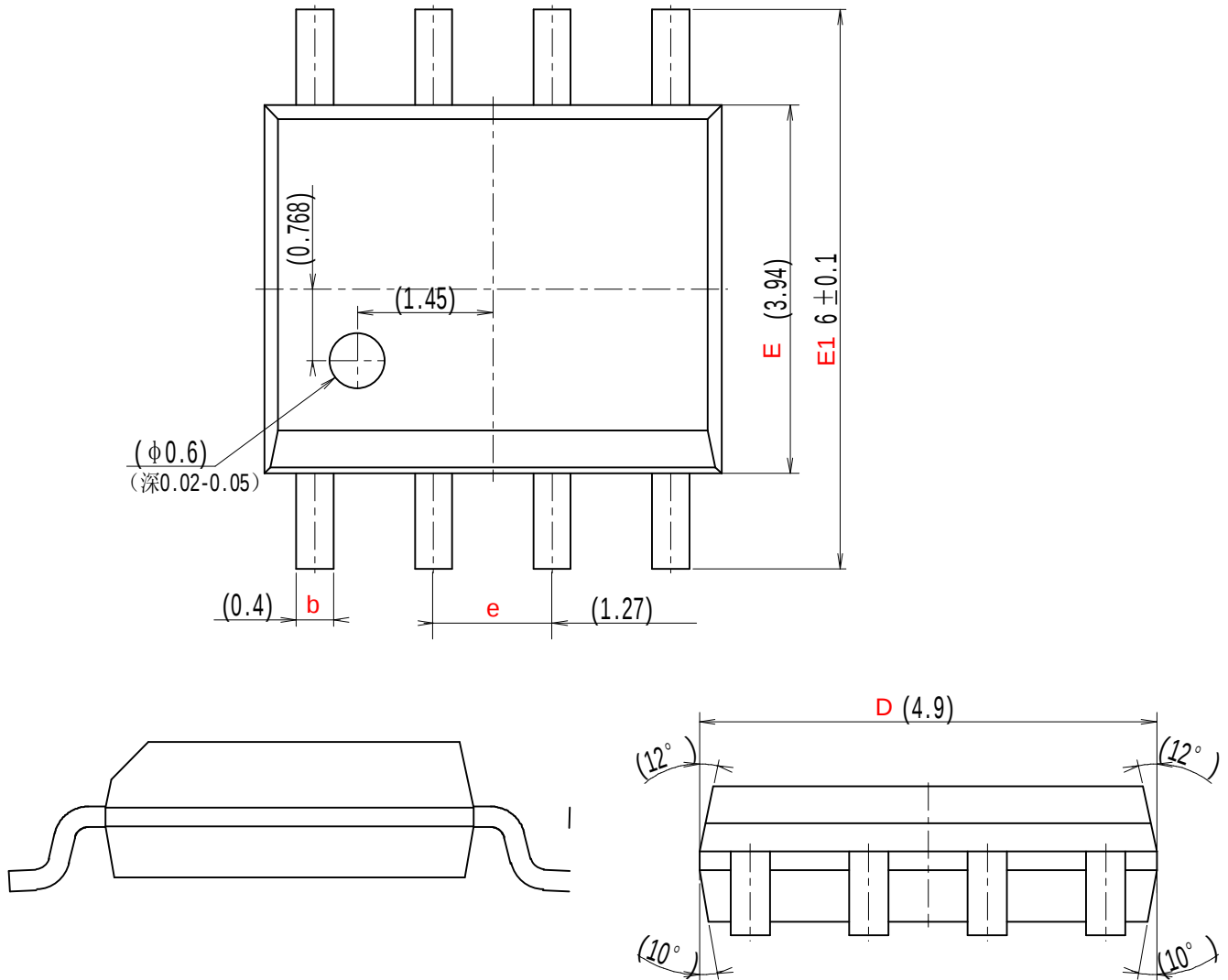
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



SOP8 PACKAGE OUTLINE DIMENSIONS



字符	Dimension millimeters		
	Min	Standard	Max
A	1.500	1.600	1.700
A1	0.050		
A2	1.350	1.450	1.550
b	0.300	0.400	0.500
c	0.220	0.254	0.280
D	4.800	4.900	5.000
E	3.840	3.940	4.040
E1	5.900	6.000	6.100
e		1.27 (BSC)	
L	0.520	0.620	0.720
θ	0°		8°